DOCKET NO: 287800US26PCT

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :

MASAYUKI OIKAWA, ET AL. : EXAMINER: CHAN, CEDRIC A.

SERIAL NO: 10/574,286 :

FILED: MARCH 31, 2006 : GROUP ART UNIT: 1797

FOR: INSPECTION METHOD AND INSPECTION ASSISTING DEVICE FOR QUARTZ PRODUCT OF SEMICONDUCTOR PROCESSING APPARATUS

## AMENDMENT UNDER 37 C.F.R. §1.111

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated February 22, 2010, please amend the aboveidentified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 9 of this paper.